

**AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1           Claim 1 (previously presented): A probe card comprising:

2           a base plate; and

3           a probe being a member in a shape of a half circle arc, formed on and supported at one end  
4 thereof by a surface of the base plate and having a top portion located at almost the center of the  
5 probe serving as a contact surface for contacting with an electrode of a measurement objective  
6 wherein

7           the probe has a first quarter circle arc portion which is supported at one end thereof by the  
8 base plate and a second quarter circle arc portion which is connected to the other end of the first  
9 quarter circle arc portion and a little shorter than the first quarter circle arc portion, and the top  
10 portion of the probe is brought into contact with an electrode of the measurement objective and  
11 elastically deformed and thereby a distal end of said second quarter arc portion is brought into  
12 contact with said base plate and slides.

1           Claim 2 (currently amended): A probe card according to claim 1, wherein a projected contact  
2 terminal is provided at the top portion ~~thereof~~ of said probe.

1           Claim 3 (currently amended): A probe card according to claim 1, wherein the distal end  
2           portion of the second quarter circle arc portion ~~thereof~~ of said probe is spherical.

1           Claim 4 (previously presented): A probe card according to claim 1, wherein coating is  
2           applied on the distal end surface of the distal end portion of the second quarter circle arc portion.

1           Claim 5 (currently amended): A probe card according to claim 1, ~~in which~~ wherein a  
2           material necessary for raising a Young's modulus is incorporated into said probe.

          Claim 6 (canceled).

1           Claim 7 (previously presented): A probe card according to any of claims 1 to 5, wherein  
2           coating is applied on a portion of a surface of the base plate in contact with the distal end surface of  
3           the second quarter circle arc portion.

1           Claim 8 (previously presented): A probe card according to any of claims 1 to 5, wherein a  
2           reinforcing member with an elasticity higher than the probe and is provided integrally with the probe  
3           on a surface thereof facing the base plate along the length direction.

1           Claim 9 (previously presented): A probe card according to any of claims 1 to 5, wherein a  
2           reinforcing member with an elasticity higher than the probe is provided between the base plate and  
3           a surface of the probe on the other side thereof from the top portion thereof.

1           Claim 10 (new): A method of measuring, comprising:  
2           measuring at least one electric characteristic of a measurement object, said measuring being  
3           performed by a probe card having at least one arch type probe.

1           Claim 11 (new): The method according to claim 10, wherein the at least one arch type probe  
2           is distinguishable from a needle-like probe.

1           Claim 12 (new): The method according to claim 11, wherein  
2           the at least one arch type probe has an arc shape, is formed on and supported at one end  
3           thereof by a surface of a base plate of the probe card, and has a contact surface portion for contacting  
4           with at least one electrode of the measurement objective, and  
5           the at least one arch type probe has a first arc portion which is supported at one end thereof  
6           by the base plate and a second arc portion continuing from the other end of the first arc portion.

1           Claim 13 (new): The method according to claim 12, further comprising:  
2           contacting the contact surface portion of the at least one arch type probe with the at least one

3 electrode of the measurement objective, wherein

4 the second arc portion is brought into contact with the base plate and slides when said  
5 contacting is performed.

1 Claim 14 (new): The method according to claim 13, wherein the second arc portion is shorter  
2 than the first arc portion.

1 Claim 15 (new): A probe card, comprising:  
2 at least one arch type probe being mounted to the probe card, the at least one arch type probe  
1 being used to measure at least one electric characteristic of a measurement object, wherein the at  
2 least one arch type probe is distinguishable from a needle-like probe.

1 Claim 16 (new): The probe card according to claim 15, further comprising:  
2 a base plate; and  
3 a contact surface portion serving as a contact surface for contacting at least one electrode of  
4 the measurement objective, wherein  
5 the at least one arch type probe has a shape of an arc, is formed on and supported at one end  
6 thereof by a surface of the base plate of the probe card, and  
7 the at least one arch type probe has a first arc portion which is supported at a first end thereof  
8 by the base plate and a second arc portion continuing from a second end of the first arc portion.

1           Claim 17 (new): The probe card according to claim 16, wherein  
2           when the contact surface portion of the at least one arch type probe is contacted to the at least  
3           one electrode of the measurement objective, the second arc portion is brought into contact with the  
4           base plate and slides.

1           Claim 18 (new): The probe card according to claim 17, wherein the second arc portion is  
2           shorter than the first arc portion.

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